

September 2009

FDFME3N311ZT

Integrated N-Channel PowerTrench® MOSFET and Schottky Diode 30 V, 1.6 A, 299 m Ω

Features

- Max $r_{DS(on)}$ = 299 m Ω at V_{GS} = 4.5 V, I_D = 1.6 A
- Max $r_{DS(on)}$ = 410 m Ω at V_{GS} = 2.5 V, I_D = 1.3 A
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600V (Note3)
- RoHS Compliant



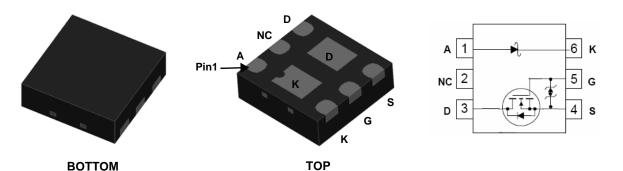
General Description

This device is designed specifically as a single package solution for a boost topology in cellular handset and other ultra-portable applications. It features a MOSFET with low input capacitance, total gate charge and on-state resistance. An independently connected schottky diode with low forward voltage and reverse leakage current to maximize boost efficiency.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

Applications

■ Boost Functions



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage			±12	V
ı	Drain Current -Continuous	T _A = 25°C	(Note 1a)	1.6	۸
ID	-Pulsed			4.5	A
D	Power Dissipation	T _C = 25°C		1.1	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	0.5	VV
V_{RRM}	Schottky Repetitive Peak Reverse Voltage			28	V
Io	Schottky Average Forward Current			1	Α
T _J , T _{STG}	Operating and Storage Junction Temperature	Range	(Note 4)	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	110	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	234	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1c)	95	C/VV
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1d)	210	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
1T	FDFME3N311ZT	MicroFET 1.6x1.6 Thin	7"	8mm	5000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	octeristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μА

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.5	1	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		-3		mV/°C
		$V_{GS} = 4.5 \text{ V}, I_D = 1.6 \text{ A}$		235	299	
r _{DS(on)}	r _{DS(on)} Drain to Source On Resistance	$V_{GS} = 2.5 \text{ V}, I_D = 1.3 \text{ A}$		296	410	mΩ
, ,	$V_{GS} = 4.5 \text{ V}, I_D = 1.6 \text{ A}, T_J = 150 ^{\circ}\text{C}$		327	420		
9 _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 1.6 \text{ A}$		2.8		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45 V V 6 V	55	75	pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	15	20	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	7	10	pF
R_g	Gate Resistance		7.5		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		6	12	ns
t _r	Rise Time	V_{DD} = 15 V, I_{D} = 1.6 A V_{GS} = 4.5 V, R_{GEN} = 6 Ω	8	16	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6.12$	22	35	ns
t _f	Fall Time		1.4	2.8	ns
Q_g	Total Gate Charge	V _{GS} = 4.5 V	1	1.4	nC
Q _{gs}	Gate to Source Gate Charge	V _{DD} = 15 V	0.2		nC
Q_{gd}	Gate to Drain "Miller" Charge	I _D = 1.6 A	0.3		nC

Drain-Source Diode Characteristics

I _S	Maximum continuous Drain-Source Diode Forward Current			1.6	Α
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 0.9 \text{ A}$ (Note 2)	0.9	1.2	V
t _{rr}	Reverse Recovery Time	I _F = 1.6 A, di/dt = 100 A/μs	12	22	ns
Q _{rr}	Reverse Recovery Charge	iF = 1.0 A, αί/αι = 100 Α/μS	3.1	10	nC

Schottky Diode Characteristics

	I _R Reverse Leakage	V _R = 28 V	T _J = 25 °C	15	100	μА
¹R			T _J = 85 °C	0.46	4.7	mA
V-	Forward Voltage	I _E = 1 A	$T_J = 25 ^{\circ}\text{C}$ $T_J = 85 ^{\circ}\text{C}$	0.47	0.57	\/
٧F	V _F Forward Voltage	IF = I A	$T_J = 85 ^{\circ}C$	0.45		V
V	Forward Voltage	I _F = 500 mA	T _J = 25 °C T _J = 85 °C	0.38	0.48	\/
V _F	V _F Forward Voltage	IF = 500 IIIA	T _J = 85 °C	0.33		V

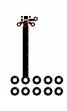
Electrical Characteristics

Notes:

- 1. R_{0,1A} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,1C} is guaranteed by design while R_{0,1A} is determined by the user's board design.
 - (a) MOSFET $R_{\theta JA}$ = 110 °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
 - (b) MOSFET $R_{\theta JA}$ = 234 °C/W when mounted on a minimum pad of 2 oz copper. For single operation.
 - (c) Schottky $R_{\theta,JA} = 95$ °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062" thick PCB.
 - (d) Schottky $R_{\rm BJA}$ = 210 °C/W when mounted on a minimum pad of 2 oz copper. For dual operation.



a. 110 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 234 °C/W when mounted on a minimum pad of 2 oz copper.



c. 95 °C/W when mounted on a 1 in² pad of 2 oz copper.



d. 210 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < $300\mu s$, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.
- 4. Rating is applicable to MOSFET only.

Typical Characteristics T_J = 25°C unless otherwise noted

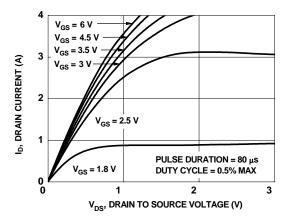


Figure 1. On Region Characteristics

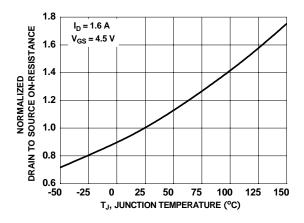


Figure 3. Normalized On Resistance vs Junction Temperature

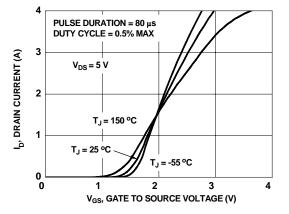


Figure 5. Transfer Characteristics

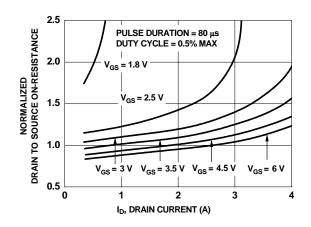


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

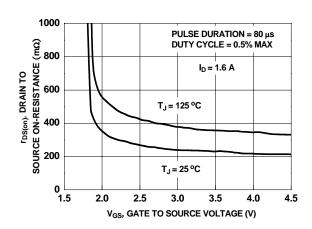


Figure 4. On-Resistance vs Gate to Source Voltage

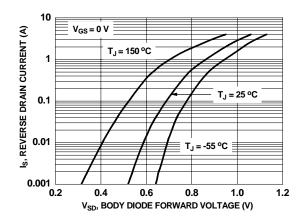


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

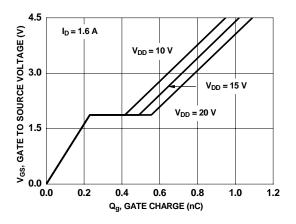
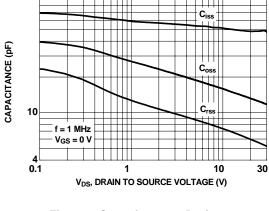


Figure 7. Gate Charge Characteristics



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Figure 8. Capacitance vs Drain to Source Voltage

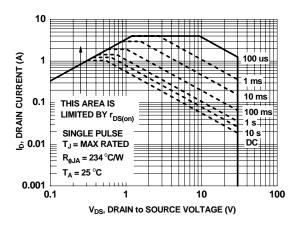


Figure 9. Forward Bias Safe Operating Area

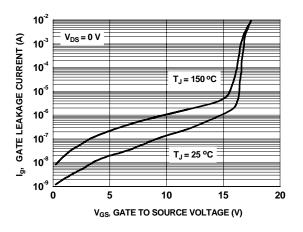


Figure 10. Gate Leakage Current vs Gate to Source Voltage

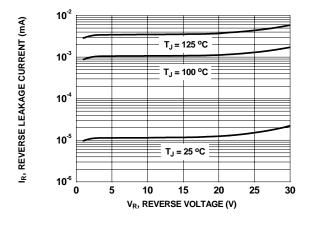


Figure 11. Schottky Diode Reverse Current

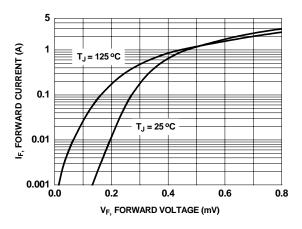


Figure 12. Schottky Diode Forward Voltage

Typical Characteristics $T_J = 25$ °C unless otherwise noted

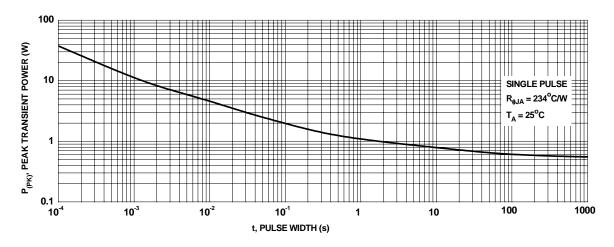


Figure 13. Single Pulse Maximum Power Dissipation

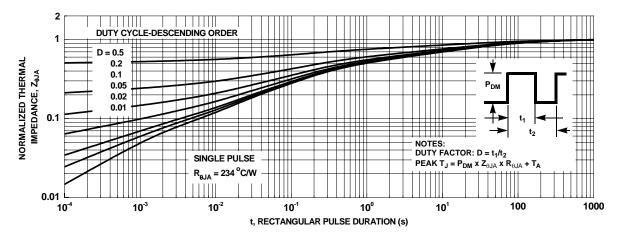
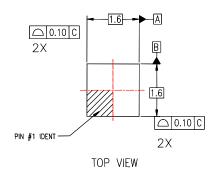
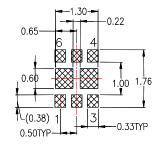


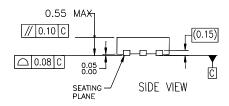
Figure 14. Junction-to-Ambient Transient Thermal Response Curve

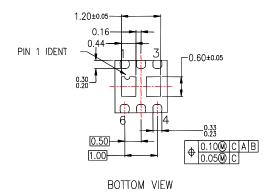
Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN









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